

**IECEE**

**CB-SCHEME**

**OD-CB2018-Ed.8.2**

**OPERATIONAL & RULING DOCUMENTS**

**IECEE GROUPS: WORKING GROUPS  
AND TASK FORCES**

**OD-CB2018-Ed.8.2**

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**IEC System for Conformity Testing and  
Certification of Electrotechnical Equipment  
and Components  
CB Scheme**

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**BOA (Board of Appeals)**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
<b>BOA (Board of Appeals)</b>	<b>CMC</b>	<p><b>Don MADER (UL), Chairman</b>  <u>Members:</u>            Joe GRYN (Underwriters Laboratories of Canada Inc.)            Paul MOLISKI (ITS USA as of 2009-01-01)            Trond SOLLIE (NEMKO)            Bo YUMIN (CNCA)            Yoji ONO (JQA)</p> <p><u>Deputies:</u>            Gerhard DREGER (VDE)            Paul TAN (PSB Corp.)            Jukka VUORINEN (SGS Fimko)            Ted GAERTNER (KEMA)</p>	<p>a) to recommend a solution to any dispute referred to it with regard to the application of these basic rules, and            b) to recommend actions to be taken against NCBs and CBTLs on complaints received regarding potential infringements to the Rules that could compromise the credibility of the IECEE Schemes.            c) to report to the CMC, for appropriate action, any observations relating to the technical content of the standards accepted for use in the IECEE and their applications, that has become evident when investigating a dispute</p>	

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## PAC (previously AAG)

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
<b>PAC</b>	<b>CMC</b>	<b>P.de RUVO (IECEE Secretary) - Chair</b> J. XIE (CNCA – Vice Chairman) Jing BIAN (CQC) Gerhard DREGER (VDE) Joe GRYN (Underwriters Laboratories of Canada Inc.) Alberto PEDERNESCHI (IMQ) Masahiro SATO (JET) Trond SOLLIE (NEMKO) Wolfgang KREINBERG (TUV PS) Ted GAERTNER (Kema) Jung Sup KIM (KTL) Observer as member of PAAG: Craig DIACK-EVANS (ASTA)	<ul style="list-style-type: none"> <li>•To monitor the Peer Assessment Program</li> <li>•To determine common understanding of ISO/IEC Guide 65 and ISO/IEC 17025</li> <li>•To clarify matters pertaining to Certification issues</li> <li>•To evaluate the Assessment Reports of candidate NCBs and CBTLs and make recommendations to the CMC</li> <li>•To support and contribute as lecturers at the IECEE Lead and Technical Assessor training courses</li> </ul>	
<b>PAC SG1</b> (previously WG 11)  <b>"PEER ASSESSMENT DOCUMENTS"</b>		P. de RUVO (Convenor) Don MADER (UL INC) Trond SOLLIE (NEMKO) Wolfgang KREINBERG (TUV PS)  Alberto PEDERNESCHI (IMQ)  Joe GRYN (Underwriters Laboratories of Canada Inc.)	Maintenance of NCB and CBTL assessments reports	

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**CAG (Chairman's Advisory Group)**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
<b>CAG (Chairman's Advisory Group)</b>	<b>CMC</b>	<b>Gosta FREDRIKSSON (IECEE Chairman)</b> Pierre de RUVO (IECEE Executive Secretary) Jun XIE (IECEE Vice-Chairman) Fritz BEGLINGER (Treasurer IECEE) Don MADER (UL) Trond SOLLIE (NEMKO) Kurt HEINZ (TÜV Rh JAPAN) Kiyoto MITSUI (JISC) Gerhard DREGER (VDE) Joe GRYN (Underwriters Laboratories of Canada Inc.) Wolfgang KREINBERG (TUV PS) Ex-Officio: Aharon AMIT (General Secretary IEC)	To advise the IECEE Officers on issues that are decided by the Chairman and tabled at each meeting.	February 25 <sup>th</sup> , 2004

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# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

## POLICY & STRATEGY FORUM

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
Policy & Strategy Forum	CMC	<p><b>G. Fredriksson (Convenir)</b> <b>P. de RUVO (Secretary)</b></p> <p><b>Senior Conformity Assessment Delegate Members</b> Joe Gryn (Underwriters Laboratories of Canada Inc.) Du Chunjing (CNCA) Alternate: Bian Jing (CQC) Gerhard Dreger (VDE) Jukka Vuorinen (SGS Fimko Ltd) Michel Brenon (LCIE) Giancarlo Zappa (IMQ) Toshiyuki Nawata (JISC) Mike Lawson (ASTABEAB) Don Mader (UL Inc) Alternate: Dave Surber (TUV Rheinland) Gitte SCHJOTZ (UL Demko) Franklin Willemstein (KEMA) Fredrik Wennersten (Intertek SEMKO) Daniel Goldstein (SII) Yoji Ono (JQA)</p> <p><b>Senior Industry Delegate Members:</b> Bill Bryans (BryBrook Consulting) YU Zida (China Haier Group Corporation) Uwe Kampet (BSH) Alternate: Jörg Hartge (ZVEI) Jari Yli-Juuti (ABB Finland) Jean-Pierre Isnard (FIEEC) Giovanni Cassinelli (Bticino S.p.A) Alternate Matteo Gavazzeni (GEWISS S.p.A) Toshiyuki Kajiya (Panasonic) Bob Taylor (Coutant Lambda Ltd.) Richard Pescatore (USNC/IECEE) Alternate: John Mahanna (IBM) Tim Duffy (Rockwell Automation) Wim Honig (Philips) Stefan Kjellnäs (ABB) Yehuda Haiman (The metal, Electrical &amp; Infrastructure Industries Association)</p>	<p>To identify market needs and propose IECEE market solutions to meet those needs and to maintain high quality third party conformity assessment principles.</p> <p>To propose mechanisms for ensuring that the IECEE Conformity Assessment solutions are recognized as the basis for certification and acceptance in regulated markets world wide in a timely way.</p> <p>To develop a framework or road map for the development of conformity assessment solutions within the IECEE scheme including such elements as:</p> <p>a) Type Test Certification b) Access to the marks of other Certification Bodies c) Full Certification Scheme. d) IECEE Conformity Assessment solutions that facilitate market access and relevance, including SDoC.</p>	2008-06-09



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# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

## CMC - WORKING GROUPS

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
<b>CMC-WG 2</b>  "Business Development"	CMC	<b>Wolfgang KREINBERG (TUV PS-Convenor)</b> Toshiyuki NAWATA (JISC) Kenji FUKASAWA (JQA) Kurt HEINZ (TUV RH JP) Uwe KAMPET (GERMAN-NC/IECEE) Representative ASIA-PACIFIC Trond SOLLIE (NEMKO) Jukka VUORINEN (SGS Fimko) Yaacov WACHTEL (SII) Steven MARGIS (UL) Fulvio GIORGI (IMQ) <b>Ron Collis (Rockwell Automation)</b> <b>Nick Maalouf (QPS)</b>	To explore further the market needs focusing around the electrotechnical sector (i.e. EMC, etc.) as well as other fields of interest for the industry. To analyze and survey any possible business development services that could be of interest for the IECEE	To be determined
<b>CMC-WG 3</b>  "MTL"	CMC	<b>Michel BRENON (LCIE Secretary-Convenor)</b> Joe GRYN (Underwriters Laboratories of Canada Inc.) Fulvio GIORGI (IMQ) Randolf KELLER (TÜV Rh Jap) Tuneyuki SATO (JET) Wolfgang KREINBERG (TÜV P.S.) Robin TIZZARD (BSI) Richard PESCATORE (USNC/IECEE) Jim CONROY (ITS Boxborough) Alternate: Craig DAVENPORT (ITS) <b>Jola Wroblewska (UL INC)</b> Ilan CARMIT (SII) Tim Duffy (Rockwell Automation)	To analyse and develop procedures related to the Manufactory Testing Laboratories programme.	<b>September 19<sup>th</sup>, 2002, Geneva, IECEE Secretariat, Salle Bois</b>
<b>CMC-WG 4</b>  "Components Acceptance"	CMC	<b>Jola WROBLEWSKA (UL-Convenor)</b> Joe GRYN (Underwriters Laboratories of Canada Inc.) Bill FISKE (USNC) Mohd Nazif (SIRIM) Ilan Carmit (SII) Mr. Ray Jefferis (ASTABEAB)	To identify component standards	Re-activated following the 2006 CMC meeting



# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
<b>CMC-WG 5</b> <b>"Components Strategic"</b>	CMC	<b>Paul Moliski (Convenor)</b> <b>(ITS U.S.A.)</b> Klaus KRESS (VDE – DE MB) Marvin MAALOUF (ENTECLA – CA MB) Joe GRYN (Underwriters Laboratories of Canada Inc.) Fulvio GIORGI (IMQ - IT MB) Jola WROBLEWSKA (UL – USNC MB) Bill FISKE (ITS N.A. – USNC MB) Jean LANZO (LCIE - FR MB)) Ted Gaertner (KEMA) Bill Burr (CSA International)	<ol style="list-style-type: none"> <li>1. Examine the current operational practices in the CB Scheme with respect to acceptance of components.               <ol style="list-style-type: none"> <li>a) Review the results of the survey carried out by the CMC-WG Component.</li> <li>b) Review the newly developed Guide converted into a Current Decision, Annex 1 of OD-CB2022, that has replaced Decision 1D115 on Acceptance of Components, to identify all situations in which components evaluated in an end-product by the issuing NCB may be not accepted by the recognizing NCB.</li> </ol> </li> <li>2. Carry out a strategic analysis of the current and future needs of the CB Scheme and the FCS with respect to acceptance of components.</li> <li>3. Develop a proposal or proposals to substantially improve the acceptance of components, with particular emphasis on the needs and expectations related to FCS.</li> </ol>	<b>To be determined</b>
<b>CMC-WG 6</b> <b>"IECEE International Mark"</b>	CMC	<b>Maarten VAN DER DUSSEN (Convenor)</b> Roy Jacobi (SAI Global) Jean-Louis ROBERT (CANADIAN-NC/IECEE) Gösta FREDRIKSSON (SEMKO) Rob FENNELL (CSA) Jonathan KOTRBA (TUV N.A.) Jola WROBLEWSKA (ULI) William H. JOHNSON (USNC/IECEE)	To explore further the idea of an International Mark monitored by the IEC.	WG disbanded following 2002 CMC Meeting, task transferred to CAB WG 7
<b>CMC-WG 7</b> <b>"Interrelation between NCBs and CBTLs"</b>	CMC	<b>Donald A. MADER (Convenor)</b> Joe GRYN (Underwriters Laboratories of Canada Inc.) Wolfgang KREINBERG (TUV PS)	To update the “examples of NCBs/CBTLs combinations” and provide additional clarifications.	WG Disbanded 2002-06



# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
CMC-WG 8 "F.A.P."		<b>Trond SOLLIE, NEMKO (Convenor)</b> Bill Rannard (SAI Global) Joe GRYN (Underwriters Laboratories of Canada Inc.) Nick MAALOUF (ENTECLA CA) Lu MEI (CQC) Thomas BILZ (VDE) Alberto PEDERNESCHI (IMQ) Richard PESCATORE (USNC/IECEE) Donald MADER (UL INC)	To further develop the necessary Procedure and Forms for a Factory Audit Program	WG disbanded following the creation of the FIC after the 2006 CMC Meeting
CMC-WG 9 "TRF"	CMC	<b>Jola WROBLEWSKA (UL) (Convenor)</b> Mauro CASARI (IMQ) Klaus KRESS (VDE)) Richard PESCATORE (USNC/IECEE) Werner HAAB (UL DE) Ralf Knapp (TUV Rh Japan)	To deal with matters pertaining to TRFs	Task completed 2001
CMC-WG 10 "Maintenance of the IECEE Rules and Operational Documents"	CMC	<b>Pierre de RUVO (IECEE)</b> Gosta FREDRIKSSON (IECEE Chairman) Jun XIE (IECEE Vice-Chairman) Fritz BEGLINGER (Treasurer IECEE) <b>Jola Wroblewska (UL INC)</b> Trond SOLLIE (NEMKO) Kurt HEINZ (TÜV Rh JAPAN) Kiyoto MITSUI (JISC) Gerhard DREGER (VDE) Joe GRYN (Underwriters Laboratories of Canada Inc.) Wolfgang KREINBERG (TUV PS) Alberto PEDERNESCHI (IMQ)	<b>To Review and update the IECEE Basic Rules, IECEE 01, the Rules of Procedure, IECEE 02, and those Operational Documents that are not under the terms of reference of existing IECEE Working Groups. To Review Current Decisions that are not within the scope of existing IECEE Working Groups and to incorporate them in the IECEE Rules, IECEE 01, the IECEE Rules of Procedure, IECEE 02 or Operational Documents as appropriate. To Refer Current Decisions that are within the scope of existing IECEE Working Groups to the appropriate WGs for incorporation into the appropriate Operational Document(s)</b>	
CMC-WG 12 "Acceptance"		Gerhard DREGER (VDE) ( <b>Convenor</b> ) Johnny Jensen (UL)	To determine the mechanisms of seeking scope extension to new	



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
and Use of IEC Standards"		International DEMKO A/S) Bill Fiske (I.T.S NA) Joe Gryn (Underwriters Laboratories of Canada Inc.) Osmo Väyrynen (SGS Fimko) Donald Mader (Observer) Masahiro Sato (JET) Tshepo Motsoane (SABS)	published IEC standards, Editions, Amendments and responsibilities from NCBs when they seek scope extension of new published standards	
CMC-WG 13 "FCS Operations"		<b>Trond SOLLIE, NEMKO (Convenor)</b> Joe GRYN (Underwriters Laboratories of Canada Inc.) Alberto PEDERNESCHI (IMQ) Donald MADER (UL INC) Ted Gaertner (KEMA)		
CMC-WG 14 "Public Information"	CMC	<b>Kurt K. HEINZ (TUV RH JP) (CONVENOR)</b> Bill BRYANS (BryBrook Consulting) Michel BRENON (LCIE) Alberto PEDERNESCHI (IMQ) Japan Richard PESCATORE (USNC/IECEE)	To Consider the Japanese proposal in light of the real market needs and propose a database that in addition to providing selected information related to the content of issued CB Test Certificates could also consider the issue pertaining to the National Differences	
CMC-WG 15 "Database"	CMC	<b>Paul TAN (PSB) (CONVENOR)</b> Wei CHEN (CQC) Yun ZHANG (CQC) Weng-Hoe CHONG (PSB) Len FLEMING (BEAB) Jola WROBLEWSKA (UL Inc.) Bill BRYANS (BryBrook Consulting)	To study the feasibility of a master searchable database that would have a global use within the IECEE operations and administration	
CMC-WG 16 "Satellite Laboratories"	CMC	<b>Don MADER, UL Inc. (CONVENOR)</b> Joe GRYN (Underwriters Laboratories of Canada Inc.) Wolfgang KREINBERG (TUV PS) Michel BRENON (LCIE) Bill FISKE (ITS-USA) Johnny JENSEN (UL DEMKO)	To develop a Draft OD that integrates the various comments and concerns as well as the impact measurements.	
CMC-WG 17 "PV Manufacturers Assessment, Surveillance"	CMC	<b>L. Ji, UL Inc. (Convenor)</b> K. Shirai (JET) W. Herrmann (TUV RH) A. Pederneschi (IMQ) Mr. Arnd Roth (VDE) Soo-Hyun PAIK (KTL)	To develop the required elements for initial assessment, continuing surveillance and audit for manufacturers producing photovoltaic equipment	WG disbanded and assigned to FIC after the 2008 CMC



# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
and Audit requirements “		Philippe GUILLON (LCIE)	under the IECEE CB Scheme category for photovoltaic equipment.	Meeting
<b>CMC-WG 20</b> “Hazardous Substances”	CMC	<b>Jukka Vuorinen, SGS Fimko (Convenor)</b> Ron Collis (Rockwell Automation) Dr. Ma Qiju (CQC) Alternate : Ms. Hu Nan (CQC) Michel Brenon (LCIE) Uwe Kampet (GERMAN-NC/IECEE) Karl Sander (TÜV RH DE) Toshiyuki Kajiya (JISC) Ted Gartner (KEMA Quality B.V.) Tim Duffy (Rockwell Automation)	The WG is tasked to identify the elements and procedures that can be used for product's testing and evaluation of Hazardous Substances.	<b>2006-11-27</b>
<b>CMC-WG 21</b> “CBTC Recognition Process”	CMC	<b>Gunsimar Paintal, Underwriters Laboratories of Canada Inc. (Convenor)</b> Michel Brenon (LCIE) Wolfgang Kreinberg (TUV PS)	<ul style="list-style-type: none"> <li>· evaluate the elements that are currently leading to a slowing down of the Recognition process</li> <li>· determine and propose the corrective actions that could overcome the reason of the slow down</li> <li>· recommend the necessary actions to improve the “Recognition” process of CB Test Certificates by Members NCB without unnecessary</li> </ul>	
<b>ad hoc CMC-WG 22</b> “Validity of IECEE Certificates”	CMC	<b>Kurt Heinz, TUV RH JP (Convenor)</b> Alberto Schiuma (IRAM) Jason Cooke (SAI Global) Bill Bryans (BryBrook Consulting) Fulvio Giorgi (IMQ) Toshiyuki Kajiya Isaac Thabo Mabena (SABS) Alternate: David Surber (TUV RH NA)	Analysis of the implications for the parties regarding the introduction of validity of CB Test Certificates and the most appropriate mechanism to establish a term of validity for CB Test Certificates.	
<b>CMC-WG</b> “IECEE MEE Task Force”	CMC	<b>Alfred Dolan (convenor)</b> Irina Antonov (SII) Michel Brossoit (CSA International) Ted Gaertner (CTL ETF 3 Convenor) Steli Loznen (Convenor IEC/TC62/SC62A/WG17) Richard J. Markle (Philips Medical Systems) Steve McRoberts (UL	To establish a consensus with methods acceptable to determine compliance with all the relevant clauses (related to ISO 14971) of IEC 60601-1 Ed. 3. To develop a Guideline document & Work Instruction on how to	



# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
		Europe) William Midgette (FDA, USA) Joseph Murnane (UL NA) Massimo Polignano (ESAOTE S.p.A.) Geri Richter (Geri-Con) Martin Schneeberg (TUV SUD) Michael Sippl (TUV SUD / IEC SC62A) Paul Tan (TUV SUD PSB) Jola Wroblewska (WG 9 Convenor) Mauro De Angiolini (IMQ) Alex Grob (GE Healthcare)	implement the relevant clauses (related to ISO 14971) of IEC 60601-1 Ed. 3. To develop a Checklist aiming at assisting ME Industry, Official Authorities and Stakeholders around the world, Testing Laboratories and Certification Bodies to properly deal with Risk Management. To develop an addendum to the Test Report Form IEC 60601-1 to cover the overall requirements pertaining to ISO 14971. To set up the content of possible trainings to cover Risk Management issues. To be the Advisory Group on common understanding of ISO 14971 related to IEC 60601-1.	
<b>CMC-WG 23“ Counterfeit”</b>	CMC	<b>Jean-Pierre ISNARD (convenor)</b> Richard Pescatore Don Mader (UL Inc.) Toshiyuki Kajiva (Panasonic) Yu Zida (Haier) Mike Lawson (Intertek) Vladimir Filiac (EZU) Luca Taglioretti (IMQ) Katharina Seidel (TUV RH DE)	To be determined	



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCE	SCHEDULE
<b>CMC-WG 24 "Infringement"</b>	CMC	<b>Don Mader (Convenor)</b> Trond Sollie (NEMKO) Wolfgang Kreinberg (TUV SUD) Ms. Bo Yumin (CNCA) Richard Pescatore (USNC IECEE) Joe Gryn (Underwriters Laboratories of Canada Inc.) Ms P Mazibuko (NRCS) M. Brénon (LCIE) Yoji Ono (JQA)	1. Identify the various forms of infringements based on the experiences of the IECEE Secretariat and the Members of WG 24 as well. 2. Explore the infringement issues and propose appropriate administrative measures for the IECEE, including the related responsibilities. 3. Draft a set of rules to consistently manage infringements within the IECEE.	
<b>CMC-WG "ad hoc" IECEE Marketing Working Group</b>	CMC	<b>Jukka Vuorinen (Convenor)</b> Gabriela Ehrlich (IEC Head of the Marketing and Communication Department) Gitte Schjøtz (UL International Demko) Kurt Heinz (TÜV Rheinland Japan) Trond Sollie (Nemko)		

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## FCS – TASK FORCES and WORKING GROUPS

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
FCS TASK FORCE "A"	CMC	Past IECEE Secretary	To develop <ul style="list-style-type: none"> <li>◆ Questionnaire to determine what NCBs are interested in participating in the CB-FCS</li> </ul>	ON HOLD
FCS TASK FORCE "B"	CMC	Pierre de RUVO (Convenor)	To develop <ul style="list-style-type: none"> <li>◆ Mfr Conformity Assessment Procedures</li> <li>◆ Mfr Q.S. Questionnaire</li> <li>◆ Audit Report Form</li> </ul>	ON HOLD
FCS TASK FORCE "C"	CMC	Don MADER (Convenor)	To develop <ul style="list-style-type: none"> <li>◆ CAC</li> <li>◆ FCS Agreement</li> <li>◆ Rider to Agreement</li> </ul>	ON HOLD
FCS TASK FORCE "D"	CMC	Trond SOLLIE (Convenor)	To develop <ul style="list-style-type: none"> <li>◆ Application Form</li> <li>◆ Audit Check List 65</li> <li>◆ Audit Check List 25</li> <li>◆ Template Ass. Rep.</li> <li>◆ Certificate for accepted NCBs</li> </ul>	ON HOLD
WG 2 REVISION IECEE 03	EVA-G	P. de RUVO (Convenor) P. LEONG (PSB) A.PEDERNESCHI (IMQ) J. SJÖBERG (SEMKO) T. SOLLIE (NEMKO) J. WROBLEWSKA (UL)	To revise the Rules of Procedure of the CB-FCS	Pending the issue from the WG "FCS Operations"
WG 1 Peer Assessment Guidelines	EVA-G	A. PEDERNESCHI (Convenor) A.PEDERNESCHI (IMQ) T. SOLLIE (NEMKO) B.WINTHER (DEMKO)	To produce Guidelines pertaining to Peer Assessment activities	Permanent review

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**CTL WORKING GROUPS and TASK FORCES**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
<b>CTL-WG 1 Accuracy/ Uncertainty</b>		<b>R. VAICKAUSKI (UL – Convenor)</b> D. BARBINI (CSA Int.) M.LESCURE (LCIE) M. HINGOTT (TUV PS) J.OLOGBOSERE (TUV RH JP) M. ANDERSEN (NEMKO) S. SARACINO (IMQ) B. JANSSON (SEMKO) B.BREITENBACH (VDE) J.O. STILLING (INTERTEK) S. NONAKA (JAB) Z. Wang (CQC) R. Florczyk (UL Inc.)	To develop an IECEE position paper detailing the rationale why accuracy is the preferred approach for the IECEE Laboratories.  To develop a procedure/guide to be used by all CBTLs so as to show accreditors and peer assessors that the IECEE is following a consistent approach when the expression of Uncertainty Measurement is absolutely necessary, with regard to clause 5.4.6 of ISO/IEC 17025.	Revised draft for CTL agenda by March 2002
<b>CTL-WG 2 PTP</b>	<b>CTL</b>	<b>H. Bachl (CTI, Convenor)</b> M. Sato (Convenor ETF 1) R. Wunderer (Convenor ETF 2) T. Gaertner (Convenor ETF 3) A. Bretz (Convenor ETF 4) E. Parma (Convenor ETF 5) JP. Barbier (Convenor ETF 10) R. Vaickauski (Convenor WG1 & WG3) Mr. L. Ji (Convenor ETF 9) K. Wilson (UL International NZ) D. BARBINI (CSA Int.) X. Mo (CQC) Z. Egozi (SII) J. Pierce (ITS USA) I. Flemming (IFM) W. Strzelecki (Convenor ETF 11) Ms. Zhu (Convenor ETF 6) U. Krischke (Convenor ETF 12)		On Going
<b>CTL-WG 3 Editing Group</b>	<b>CTL</b>	<b>Ronald VAICKAUSKI (UL- Convenor)</b>  Hubert BACHL (CTI) Marc LESCURE (LCIE) William FISKE (ITS-USA) C.SWEE-GEE (PSB) Arkadiusz SALWA (UL Inc.)	To review the CTL Decisions sheets and to coordinate with the ETFs on the wording to be used.	On Going



# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components CB Scheme

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
<b>CTL-WG 4 Coordination</b>		<b>E. Parma (Convenor)</b> M. Sato (Convenor ETF1) R. Wunderer (Convenor ETF2) T. Gaertner (Convenor ETF3) A. Bretz (Convenor ETF 4) Ms. Zhu (Convenor ETF6) R. Vaickauski (Convenor WG1 & WG3) Mr. L. Ji (Convenor ETF 9) H. Bachl (Convenor WG2 and Convenor ETF 7 ad interim) J.P. Barbier (Convenor ETF10) W. Strzelecki (Convenor ETF11) U. Krischke (Convenor ETF 12)  Mr. Bengt Jansson (Convenor CTL ETF 13)		On Going
<b>TASK FORCE  1</b>	<b>CTL</b>	<b>M. Sato (Convenor)</b> G. Camiciotti (IMQ) Technical Advisor J.D. Gonzales (IRAM) K. Wilson (Wakefield Labs) T. Lornitzo (OVE) F. Rosenberger (OVE) G. Tarseos (CSA) H. Wang (CQC) Z. Jurda (EZU) G. Bukkjaer (UL International Demko A/S) O. Väyrynen (FIMKO) A. Barrere (LCIE) B. Poesl (TÜV Rheinland LGA Products GmbH - DE) M. Hingott (TÜV PS) D. Fietz (TÜV PS) R. Gottschling (VDE) Z. Zsákai (MEEI) J. Sumiya (JET) A. Sasaki (JQA) D. van Aalderen (KEMA) T. Ulsrud (NEMKO) E. Cardoso (IEP) E.G. Chia (PSB) M. Zontar (SIQ) R. Guirado (LCOE) L. Mattson (SEMKO) R. Slupinski (UL) J. Stimitz (UL)	Household and similar equipment (HOUS) Portable tools (TOOL) and TOYS	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		L. Yap (Intertek Shanghai) K. Park (KTL) A. Renn (TUV Rheinland HK) Y.G. Kong (KTL) J. Santos (CERTIF - PT) J.W. Byun (KETI)		
<b>TASK FORCE</b>  2	<b>CTL</b>	<b>M. Hingott (TUV SUD PS) (Convenor)</b> M. Andersen (NEMKO) Technical Advisor IEC 60065 & IEC 60950 T. Burke (UL) Technical Advisor IEC 60950 T. Shiota (JQA) Technical Advisor IEC 60065 & IEC 60950 K. Wilson (UL International New Zealand) J.D. Gonzales (IRAM) T. Thun (TGM-VAE) X. Xiao (CQC) F. Homolka (EZU) J. J. Jensen (UL International Demko A/S) T. Silonsaari (FIMKO) J. Lanzo (LCIE) H. Frerk (VDE) A. Arndt (TÜV Rheinland) K.-H. Gompf (VDE) I. Seres (MEEI) F. Brivio (IMQ) B. Burek (Intertek) T. Kuboki (JET) J. Ologbosere (TUV Rheinland Japan) Jin-Soo Kim (KTL) A. Bergervoet (KEMA) M. Ng (PSB) M. Kiselja (SIQ) B. Jansson (SEMKO) P. Cross (NEMKO) D. Bras (EMITECH) V.K. Truong (Electrosuisse) C. Sato (UL Inc.) <b>Y-S Lee (KETI)</b> <b>B Lowe (CSA International)</b> <b>E. Yap (CSA International)</b>	Electronics and entertainment (TRON) IT and office equipment (OFF)	On Going
<b>TASK FORCE</b>  3	<b>CTL</b>	<b>T. Gaertner (Convenor)</b> H. Sattler (VDE) Technical Advisor R. A. Wunderer (OPFZ) A. Parzer (TÜV-A)	Electrical equipment for medical use (MED) Measuring equipment (MEAS)	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		J. Lanzo (LCIE) O. A. Nielsen (UL International Demko A/S) M. Mentula (SGS FIMKO) M. Sippl (TUV PS, Convenor SC 62A/WG 14 - Liaison Officer) D. Fietz (TUV PS) L. Freudenreich (TÜV Rheinland) V. Ebinghaus (TÜV Rheinland) R. Schoensteiner (LGA) I. (Seres MEEI) M. De Angiolini (IMQ) M. Kiselja (SIQ) P. Lymeus (SEMKO) V.K. Truong (Electrosuisse) G. Hines (ITS T&C) J. Murnane (UL) S. Poutissou (CSA) M. Brossoit (CSA) B. Burek (Intertek) Andreas Nilsson (Nemko A.S.) J. Metter (ETI) S. Seda (ETI)		



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
<b>TASK FORCE</b>  4	CTL	<b>Andreas Bretz (VDE) (Convenor)</b> H. Bachl (CTI) Technical Advisor B. Hedlund (SEMKO) Technical Advisor B. B. Doyeo (IRAM) G. Miscovich (IRAM) C. Prochaska (TGM-VAE) S. Piras (SGS CEBEC) W. Zhang (CQC) M. Sobeslavsky (EZU) Lars T. Hansen (UL International Demko A/S) S. Lokfors (FIMKO) P. Balaire (ASTABEAB) P. Nagy (MEEI) F. Brivio (IMQ) M. Casari (IMQ) K. Hasegawa (JET) Sung-Hee Mo (KTL) H. Barends (KEMA) R. Hendriksen (KEMA) J. Costa (ISQ) J. Santos (CERTIF) E. Venek (SIQ) T. de Frutos (AENOR) M. Huber (Electrosuisse) C.S. Kurten (UL) J.S. Antony (UL) Y. Liu (CQC) I. Szecsei (MEEI) <b>J.K. Park (KTL)</b>	Installation accessories and connecting devices (INST) Switches for appliances and automatic controls for electrical household appliances (CONT) Capacitors as components (CAP) MISC	On Going
<b>TASK FORCE</b>  5	CTL	<b>E. Parma (Convenor)</b> P. Kaufmann (VDE) Technical Advisor A.D. Hughes (Thorn Lighting Ltd. - Expert from Industry) Technical Advisor B. B. Doyeo (IRAM) G. Miscovich (IRAM) C. Prochaska (TGM-VAEE) R. Stoegmuller (OVE) S. Chen (CQC) F. Jandura (EZU) G. Bukkjaer (UL International Demko A/S) W. Parmiani (UL International Italia) P. U. K. Orrevetalainen (SGS FIMKO) M. Lescure(LCIE) D. Fietz (TUV SUD PS) H. Kilb (VDE) W. Menger (VDE)	Lighting (LITE)  Safety transformers and similar equipment (SAFE)	On Going



# IEC System for Conformity Testing and Certification of Electrotechnical Equipment and Components

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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		M. Kato (JET) S. J. UK (KTL) H. Telindert (KEMA) T. Drost (KEMA) E. Venek (SIQ) A. Valladolid (LCOE) Mr. S. Poole (L.A.L.) Ms. A. Branco (CERTIF) H.-K. Tan (TUV SUD PSB) F. Tironi (FLOS - Expert from Industry) T. Andersson (SEMKO) M. Stalder (Electrosuisse) C. Maes (SGS CEBEC) S. Shen (LCIE China) R. Mantegazza (MQ) P. Painini (IMQ) P. Jong Koo (KTL) P. Bacurik (EVPU) G. Klinger (TÜV Rheinland) E. Yap (CSA International) F. Rusnati (Assil) D. Lenasi (CSA International) J. Costa (ISQ) E. Cardoso (IEP) G. Del Amo Martinez (AENOR) T. Haupt (TÜV Rheinland LGA Products gmbh)		
<b>TASK FORCE</b>  <b>6</b>	<b>CTL</b>	<b>Zhu (TICW –Convenor)</b> I. McGuinness (BSI) Technical Advisor J. Tuma (EZU) S. Lokfors (FIMKO) C. Mazzucchi (IMQ) O.A. Nielsen (UL International Demko A/S) G. Mackenbach (KEMA) F. Shirai (JET) Hoowo Kang (KTL) A.C. Figueiral (CERTIF) J.M. Cruz (ISQ) H. Chuan Wee (PSB) T. Kokelj (SIQ) N. Tjapkin (GAMA)	Cables and cords (CABL)	On Going
<b>TASK FORCE</b>  <b>7</b>	<b>CTL</b>	<b>Mr. Bachl (CTI) - Convenor ad interim</b> S. Piras (SGS CEBEC) M. Sobeslavsky (EZU) V. Fiederichs (International Product Safety GmbH) J.-F. Bruel (LCIE) S. Lautamies (FIMKO) A. Bretz (VDE)	Low voltage high power switching equipment installation (POW) Protective equipment (PROT)	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
		P. Nagy (MEEI) M. Casari (IMQ) S.P. Ahn (KERI) H. Kormelink (KEMA) A. Orte (AENOR) B. Hedlund (SEMKO) D. Mueller (Underwriters Laboratories, Inc.)		
<b>TASK FORCE 8</b>	<b>CTL</b>	<b>D.W. O'Shea (Convenor)</b> L.T. Hansen (UL International Demko A/S) N. Nakamura (JET) T. Yamada (JQA) N. Tjapkin (GAMMA)	Plastics	<b>Disbanded during the CTL meeting in Johannesburg 2006-04-18</b>
<b>TASK FORCE 9</b>	<b>CTL</b>	<b>L. Ji (UL Inc.) -Convenor</b> A. Roth (VDE) J. H. Wohlgemuth (BP SOLAREX) N. Wilmot (Murdoch University) Y. Murakami (JET) H. Barikmo (TC82) W. Kang (CQC) S. Wu (Intertek Taiwan) C. Hee (Intertek Singapore) C. Roversi (IMQ S.p.A.) S. Poutissou (CSA International) G. Bellenda (Eurofins) G. Bogdan (MEEI Kft) C. Flueckiger (UL, Inc) J. Althaus (TUV Rheinland)	Photovoltaics	On Going



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
<b>TASK FORCE</b>  <b>10</b>	<b>CTL</b>	<b>JP. Barbier (LCIE - Convenor)</b> B. Berglof (Intertek Semko) D. Rivoltella (Sicur Control, UL International Demko A/S) J. Zheng (CQC) K.W. Friedrich (TUV Rheinland) J. Nyman (Nemko) S. Kloska (VDE) A. Van Der Meijden (KEMA) H. Yamashita (JET) S.-J. Kim (KTL) J. Merikari (SGS Fimko) T. Hada (JQA) C. Cantaluppi (IMQ) G. Gamperi (TGM-VAEE) R. Guirado (LCOE) B. Delisi (UL Inc) C. Hauser (Electrosuisse) M. Mak (SIQ) J. Deng (TUV SUD PSB) J. Merikari (SGS FIMKO) Y. Litvinov (Intertek)	Electromagnetic Compatibility	On Going
<b>TASK FORCE</b>  <b>11</b>	<b>CTL</b>	<b>T. Wong (CSA International) Convenor</b> N. Stoev (CSA International) Technical Advisor R. Wunderer (OVE) K. Tachihara (JQA) Chul-Joo Jeon (KTL) A. Bergervoet (KEMA) M. Kiselja (SIQ) B. Jansson (SEMKO) V.K. Truong (Electrosuisse) I. Antonov (SII) P. Boden (UL) V. Ebinghaus (TUV RH DE) A. Roth (VDE) V. Kalakutskiy (TUV RH JP) O. Stilling (Intertek Semko Shanghai) Y. E. Teong (TUV SUD PSB) K.J. Puckett (TUV SUD PS) M. H. Han (KETI) E. Franchina (IMQ S.p.A.)	Lasers	



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<b>TASK FORCE</b>  <b>12</b>	<b>CTL</b>	<b>Dr. U. Krischke (SGS-Germany) Convenor</b> J. Han (SGS- Korea) A. Maijala (SGS- Finland) C. Chu (SGS- Taiwan) G. Fong (SGS- Taiwan) K. Goto (SGS- Japan) S. MacLeod (UL-US) M. Jahns (TUV SUD) H. Hinrichs (Bureau Veritas Consumers Product Services GmbH) M. Cheng (Nemko Shanghai) C. List (Intertek Consumer Goods GmbH) T. Norlem (Intertek Semko AB) D. Elks (Intertek) N. Sözer Güllü(Intertek Testing Services Turkey) P. Spengler (DEKRA Industrial GmbH)	Hazardous Substances	
<b>TASK FORCE</b>  <b>13</b>	<b>CTL</b>	Bengt Jansson (Intertek Semko AB) - Convenor Laurie Florence (UL Inc.) Hyun-Jong Jun (KTL) Saadia Jebnoun (LCIE Bureau Veritas) Jean Lanzo (LCIE Bureau Veritas) Kun-Jeng Liang (UL Taiwan Co., Ltd.) Sammy Wu Wu (Intertek Taiwan) Raymond Zhou (Intertek China) Jody Leber (SGS) Timo Silonsaari (SGS Fimko) Szecei (MEEI) C. Swee-Gee (TUV SUD PSB)		



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DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
<b>CMC-WG</b> “Software Evaluation Panel”	<b>CTL</b>	<b>Convenor of the Technical Panel: Rafael GUIRADO – LCOE &amp; Member of TC 61</b> <b>Members of the Technical Panel:</b> Masahiro SATO – JET & Convenor of IECEE CTL ETF 1 & Member of TC 61 Bernd GEHRKE – TC 61 & Chairman MT 23 Dieter FIETZ – TUV SUD Anura FERNANDO – UL Inc Markus Graedler - ZF Electronics GmbH Juan Carlos MOLINA MORENO – LCOE Bernhard SCHAEFERS – TUV SUD Maurizio FALORNI – IMQ Eckhard SCHWENDEMANN - ES-TMC Ralf Schwab - VDE	<ul style="list-style-type: none"> <li>• To establish a consensus with methods acceptable to determine compliance with Annex R of IEC 60335-1 and Annex H of IEC 60730-1</li> <li>• To develop a Guideline document &amp; Work Instruction for testing purposes on how to implement the Annex R of IEC 60335-1 and Annex H of IEC 60730-1</li> <li>• To develop a Checklist aiming at assisting Household Appliances Industry, Official Authorities and Stakeholders in the global market, Testing Laboratories and Certification Bodies to inform the latter with the testing procedures that are going to be applied related to the requirements as specified in Annex R of IEC 60335-1 and Annex H of IEC 60730-1.</li> <li>• To develop an addendum to the TRF IEC 60335 series to cover the overall requirements pertaining to Annex R of IEC 60335-1 and Annex H of IEC 60730-1. This task will be undertaken by the IECEE WG 9 Test Report Forms however the direct input of the Technical Panel “Software Evaluation” is recommended.</li> <li>• To set up the content of possible trainings for NCBs/CBTLs- Manufacturers-IECEE Technical Assessors to cover Software Evaluation issues.</li> <li>• To be the IECEE Advisory Group on</li> </ul>	



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**IEC CAB TECHNICAL PANEL**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
<b>IEC-CAB TECHNICAL PANEL</b>		<b>Mr. P. de Ruvo (Convenor)</b> Mr. D. Mader (UL Inc.) Mr. J. Gryn (Underwriters Laboratories of Canada Inc.) Mr. C. Agius (IECEX) Mr. U. Klausmeyer (Observer) Mr. N. Mueller ( ? ) Mr. J. Hattingh ( ? ) Mr. J. Mitchell ( ? ) Mr. C. Watson ( ? ) Ms. M. Malmqvist (SWEDAC)		

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**JWG – JOINT WORKING GROUP**

DESIGNATION	REPORTING TO	MEMBERS	TERMS OF REFERENCES	SCHEDULE
<b>JWG</b>  <b>“COMMON UNDERSTANDING OF ISO/IEC 17025”</b>		<b>Mr. de Ruvo (Convenor)</b> Mr. A. Pederneschi (IMQ) Mr. D. Mader (UL Inc.) Mr. J. Gryn (Underwriters Laboratories of Canada Inc.) Mr. J. Xie (CNCA) Mr. W. Kreinberg (TUV PS) Mr. M. Wittner (IRAM) Mr. T. Sollie (NEMKO) Mr. G. Dreger (VDE) Mr. C. Agius (IECEX) Mr. U. Klausmeyer (IECEX) Mr. N. Mueller ( ? ) Mr. J. Hattingh ( ? ) Mr. S. Sydney ( ? ) Mr. J. Mitchell ( ? ) Mr. C. Bestwick (UKAS) Mr. C. Watson ( ? ) Mr. L. Bauder (METAS) Ms. M. Malmqvist (SWEDAC)		

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